



Power MOSFETS

DATASHEET

LM1A090NAP3A

N-Channel
Enhancement Mode MOSFET

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Quality Management Systems
ISO 9001:2015 Certificate

N-Channel Enhancement Mode MOSFET

Pin Description		Ordering Information		
TO220-3L (TOP view)	Symbol	Symbol	N-Channel	Unit
		V_{DSS}	100	V
		$R_{DS(ON)-Max}$	9.3	mΩ
		I_D	72	A

Feature

- Fast switching speed
- Reliable and Rugged
- ROHS Compliant & Halogen-Free
- 100% UIS and Rg Tested

Applications

- DC-DC Converter
- Motor Control

Ordering Information

Orderable Part Number	Package Type	Form	Shipping	Marking
LM1A090NAP3A	TO220-3L	Tube	50 / Tube	1A090 <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/> <input type="checkbox"/>

Absolute Maximum Ratings (T_J=25°C Unless Otherwise Noted)

Symbol	Parameter	N-Channel	Unit
V_{DSS}	Drain-Source Voltage	100	V
V_{GSS}	Gate-Source Voltage	± 20	
T_J	Maximum Junction Temperature	150	°C
T_{STG}	Storage Temperature Range	-55 to 150	°C
$I_{DM}^{①}$	Pulse Drain Current Tested	$T_c=25^\circ\text{C}$	A
I_D	Continuous Drain Current	$T_c=25^\circ\text{C}$	A
		$T_c=100^\circ\text{C}$	
P_D	Maximum Power Dissipation	$T_c=25^\circ\text{C}$	W
		$T_c=100^\circ\text{C}$	
$I_{AS}^{②}$	Avalanche Current, Single pulse	L=0.1mH	A
$E_{AS}^{②}$	Avalanche Energy, Single pulse	L=0.1mH	mJ

Thermal Characteristics

Symbol	Parameter	Rating	Unit
$R_{θJC}$	Thermal Resistance-Junction to Case	Steady State	1.5 °C/W
$R_{θJA}$ ^③	Thermal Resistance-Junction to Ambient	Steady State	62.5 °C/W

Note ① : Max. current is limited by bonding wire

Note ② : UIS tested and pulse width are limited by maximum junction temperature 150 °C

Note ③ : Surface Mounted on 1in² FR-4 board with 1oz.

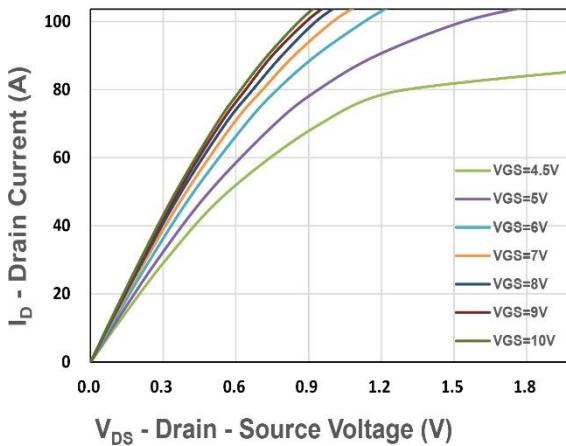
N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Electrical Characteristics						
$\mathbf{BV_{DSS}}$	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_{DS}=250\mu\text{A}$	100	-	-	V
$\mathbf{I_{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS}=80\text{V}$, $V_{GS}=0\text{V}$	-	-	1	μA
$\mathbf{V_{GS(th)}}$	Gate Threshold Voltage	$V_{DS}=V_{GS}$, $I_{DS}=250\mu\text{A}$	1	2	3	V
$\mathbf{I_{GSS}}$	Gate Leakage Current	$V_{GS}=\pm 20\text{V}$, $V_{DS}=0\text{V}$	-	-	± 100	nA
$\mathbf{R_{DS(ON)}}^{\circledast}$	Drain-Source On-state Resistance	$V_{GS}=10\text{V}$, $I_{DS}=20\text{A}$	-	7.8	9.3	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$, $I_{DS}=10\text{A}$	-	11.8	14.3	
$\mathbf{g_{fs}}$	Forward Transconductance	$V_{DS}=5\text{V}$, $I_{DS}=10\text{A}$	-	35	-	S
Dynamic Characteristics ^⑤						
$\mathbf{R_G}$	Gate Resistance	$V_{GS}=0\text{V}$, $V_{DS}=0\text{V}$, Freq.=1MHz	-	2	-	Ω
$\mathbf{C_{iss}}$	Input Capacitance	$V_{GS}=0\text{V}$, $V_{DS}=50\text{V}$, Freq.=1MHz	-	1931	-	pF
$\mathbf{C_{oss}}$	Output Capacitance		-	390	-	
$\mathbf{C_{rss}}$	Reverse Transfer Capacitance		-	32	-	
$\mathbf{t_{d(ON)}}$	Turn-on Delay Time	$V_{GS}=10\text{V}$, $V_{DS}=50\text{V}$, $I_D=1\text{A}$, $R_{GEN}=3\Omega$	-	11	-	nS
$\mathbf{t_r}$	Turn-on Rise Time		-	21	-	
$\mathbf{t_{d(OFF)}}$	Turn-off Delay Time		-	32	-	
$\mathbf{t_f}$	Turn-off Fall Time		-	15	-	
$\mathbf{Q_g}$	Total Gate Charge	$V_{GS}=4.5\text{V}$, $V_{DS}=50\text{V}$ $I_D=20\text{A}$	-	22.9	-	nC
$\mathbf{Q_g}$	Total Gate Charge	$V_{GS}=10\text{V}$, $V_{DS}=50\text{V}$, $I_D=20\text{A}$	-	41.8	-	
$\mathbf{Q_{gs}}$	Gate-Source Charge		-	5.4	-	
$\mathbf{Q_{gd}}$	Gate-Drain Charge		-	12.4	-	
Source-Drain Characteristics						
$\mathbf{V_{SD}}^{\circledast}$	Diode Forward Voltage	$I_{SD}=10\text{A}$, $V_{GS}=0\text{V}$	-	0.8	1.1	V
$\mathbf{t_{rr}}$	Reverse Recovery Time	$I_F=10\text{A}$, $V_R=50\text{V}$ $dI_F/dt=100\text{A}/\mu\text{s}$	-	48.2	-	nS
$\mathbf{Q_{rr}}$	Reverse Recovery Charge		-	78.5	-	nC

Note ④ : Pulse test (pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$).

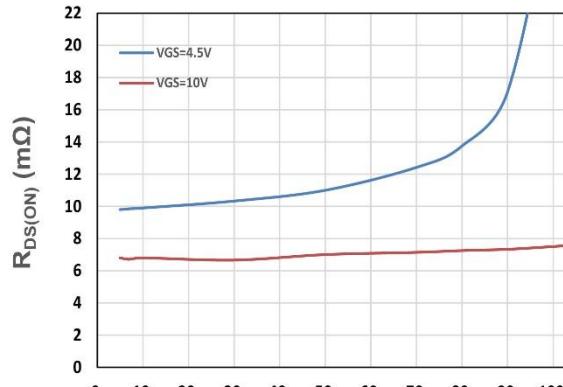
Note ⑤ : Guaranteed by design, not subject to production testing.

N-Channel Typical Characteristics



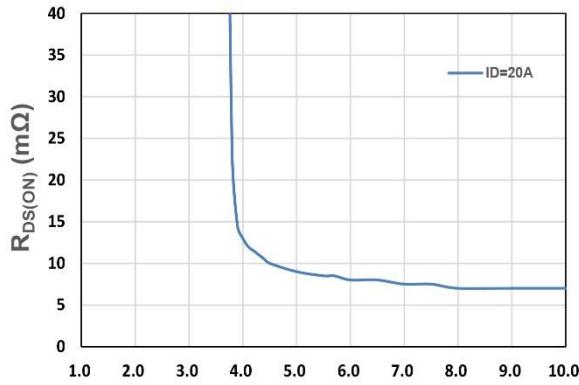
I_D - Drain Current (A)
 V_{DS} - Drain - Source Voltage (V)

Figure 1. Output Characteristics



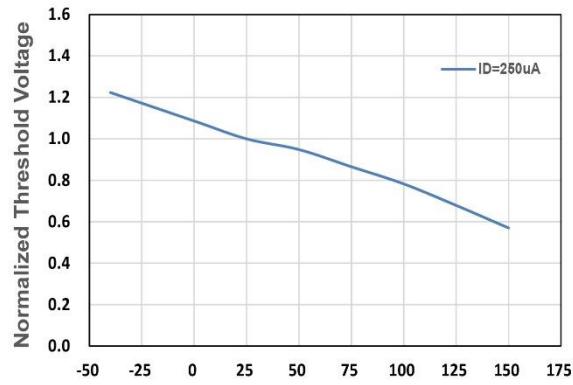
$R_{DS(ON)}$ (mΩ)
 I_D - Drain Current (A)

Figure 2. On-Resistance vs. ID



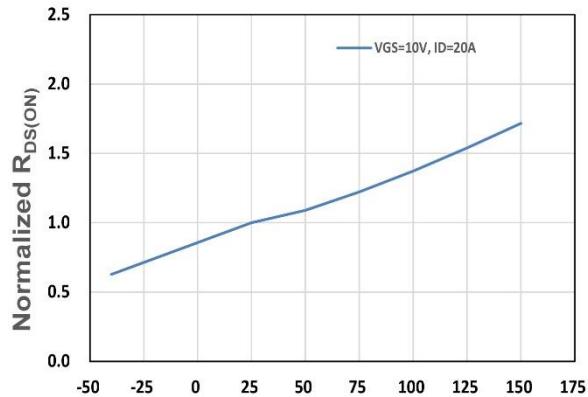
$R_{DS(ON)}$ (mΩ)
 V_{GS} - Gate - Source Voltage (V)

Figure 3. On-Resistance vs. VGS



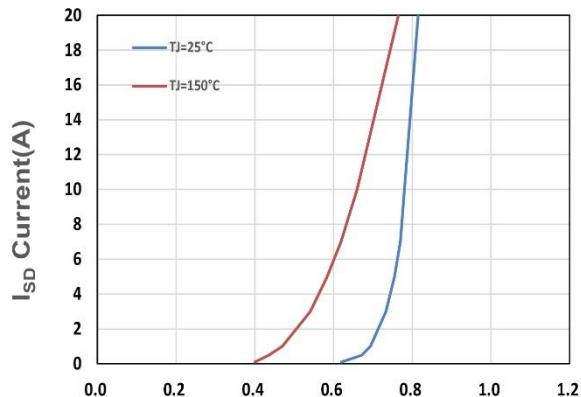
Normalized Threshold Voltage
 T_j , Junction Temperature($^{\circ}\text{C}$)

Figure 4. Gate Threshold Voltage



Normalized $R_{DS(ON)}$
 T_j , Junction Temperature($^{\circ}\text{C}$)

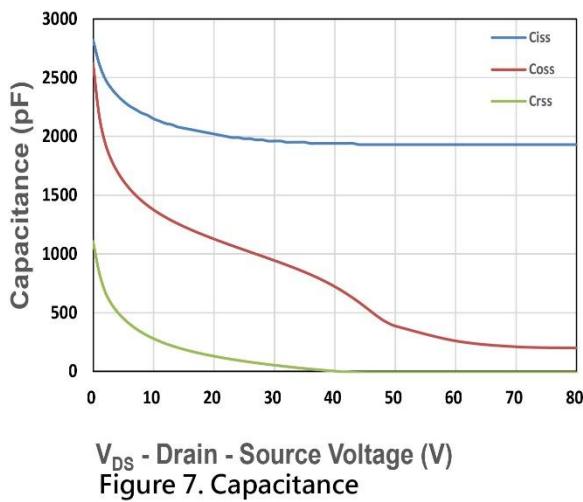
Figure 5. Drain-Source On Resistance



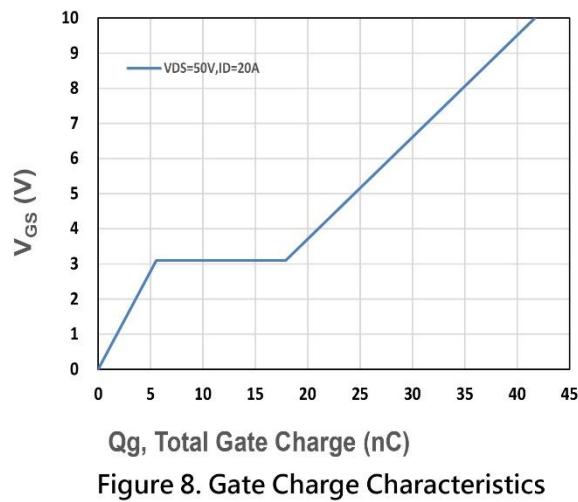
I_{SD} Current(A)
 V_{SD} , Source-Drain Voltage(V)

Figure 6. Source-Drain Diode Forward

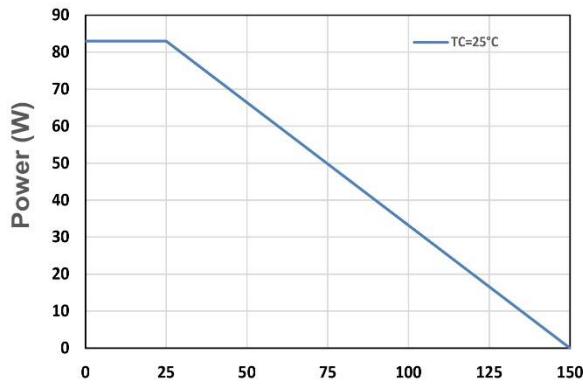
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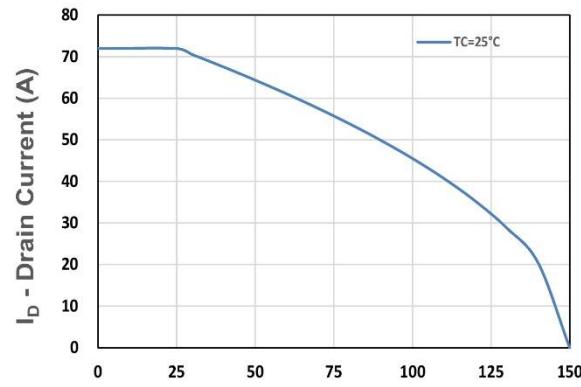
V_{DS} - Drain - Source Voltage (V)
Figure 7. Capacitance



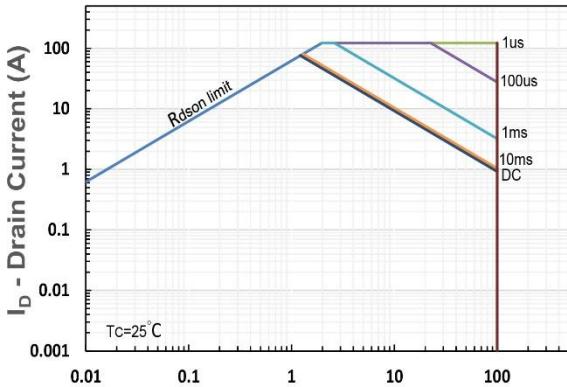
V_{GS} (V)
Q_g, Total Gate Charge (nC)
Figure 8. Gate Charge Characteristics



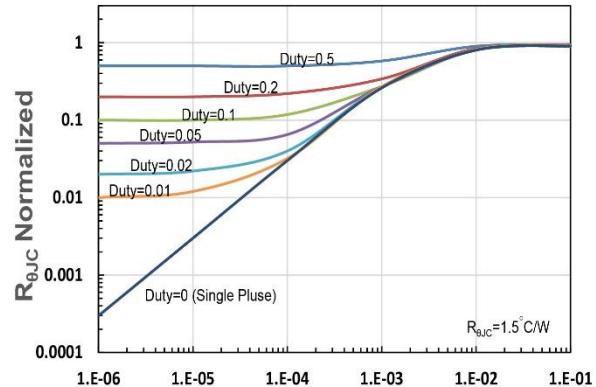
T_c - Junction Temperature (°C)
Figure 9. Power Dissipation



I_D - Drain Current (A)
T_c- Junction Temperature (°C)
Figure 10. Drain Current



V_{DS} - Drain-Source Voltage (V)
Figure 11. Safe Operating Area



t₁,Square Wave Pulse Duration(s)
Figure 12. R_{θJC} Transient Thermal Impedance